

Technical Program Committee

Chair: Daniel Arnitz Graz University of Technology (Austria), Duke University (USA)

Committee Members:

Co- Chairs:

Gildas Avoine (Belgium)
Université Catholique de Louvain

Pavel Nikitin (USA)
Intermec Technologies

Shigeya Suzuki (Japan)
Keio University

Joshua Griffin (USA)
Disney Research Pittsburgh

Matthew Reynolds (USA)
Duke University

Jin Mitsugi (Japan)
Keio University

Alanson Sample (USA)
University of Washington

Members:

Leonardo Amaral (Brazil)
Pontificia Universidade Católica do Rio Grande do Sul

Jordan Besnoff (USA)
Duke University

Michael Buettner (USA)
University of Washington

Daniel Deavours (USA)
University of Kansas

Daniel Engels (USA)
Revere Security

Michael Goller (Austria)
Enso Detego GmbH

Paul Hartmann (USA)
RF SAW, Inc.

Shan Jiang (USA)
Florida International University

Jennifer King (USA)
University of California Berkeley

Gregor Lasser (Austria)
Vienna University of Technology

Gaetano Marrocco (Italy)
University of Rome Tor Vergata

Robert Miesen (Germany)
University of Erlangen-Nuremberg

Yossef Oren (Israel)
Tel Aviv University

Josef Preishuber-Pfluegl (Austria)
CISC Semiconductor
Design+Consulting GmbH

Darindra Arumugam (USA)
Carnegie Mellon University

Rahul Bhattacharyya (USA)
Massachusetts Institute of Technology

Srdjan Capkun (Switzerland)
ETH Zurich

Laurent Dussopt (France)
CEA, LETI, Minatec

Christian Floerkemeier (USA)
Massachusetts Institute of Technology

Stephan Haller (Switzerland)
SAP (Switzerland) Inc.

Peter Hawrylak (USA)
University of Tulsa

Riad Kanan (Switzerland)
University of Applied Sciences, HES-SO Valais

Daniel Kuester (USA)
NIST

Qun Li (USA)
College of William and Mary

Iker Mayordomo (Germany)
Fraunhofer Institute for Integrated Circuits IIS

Ulrich Muehlmann (Austria)
NXP Semiconductors

Etienne Perret (France)
Grenoble-INP

Damith Ranasinghe (Australia)
The University of Adelaide

Gisele Bennett (USA)
Georgia Institute of Technology

Leonardo Bocchi (Italy)
University of Florence

Senthilkumar CP (USA)
University of Arkansas

Randolf Ebelt (Germany)
University of Erlangen-Nuremberg

Rich Fletcher (USA)
Tagsense, Inc.

Chaabane Hamza (France)
IER

Michael Hutter (Austria)
Graz University of Technology

Tom Kerr (USA)
ClearCount Medical Solutions

Robert Langwieser (Austria)
Vienna University of Technology

Giuliano Manzi (Austria)
Austriamicrosystems

Florian Michahelles (Switzerland)
ETH Zurich

Carlo Mutti (Switzerland)
FACEA

Radislav Potyrailo (USA)
General Electric

Antonio Rizzi (Italy)
University Parma

Yuki Sato (Japan)
Keio University

Joshua Smith (USA)
University of Washington

Stewart Thomas (USA)
Duke University

Ken Traub (USA)
Ken Traub Consulting LLC

Leena Ukkonen (Finland)
Tampere University of Technology

Junyu Wang (P. R. China)
Fudan University

Terry Ye (Hong Kong)
Hong Kong R&D Center for Logistics
and Supply Chain Management

Zhuo Zou (Sweden)
Royal Institute of Technology (KTH)

Botao Shao (Sweden)
Royal Institute of Technology (KTH)

Xi Tan (P.R. China)
Fudan University

Craig Thompson (USA)
University of Arkansas

Matthew Trotter (USA)
Georgia Institute of Technology

Harald Vogt (Germany)
SAP AG

Jingtian Xi (Hong Kong)
Hong Kong R&D Center for Logistics
and Supply Chain Management

David Zanetti (Switzerland)
ETH Zurich

Yanjun Zuo (USA)
University of North Dakota

Dave Singelee (Belgium)
Katholieke Universiteit Leuven

Smail Tedjini (France)
Grenoble-inp

Dale Thompson (USA)
University of Arkansas

Ming-Hsien Tsai (Taiwan)
Taiwan Semiconductor Manufacturing
Company

Jukka Voutilainen (Finland)
Voyantic

Lei Xie (P. R. China)
Nanjing University

Chenming Zhou (USA)
Disney Research Pittsburgh

Upcoming CRFID Events

IEEE RFID TA 2012

Co-located with International RFID Congress 2012
November 5 - 7, 2012
Palais de la Méditerranée
Nice, France
Contact: Smail Tedjini (smail.tedjini@grenoble-inp.fr)
www.rfid-congress.com
Pick up a Call for Papers at the IEEE RFID 2012
registration desk



Palais de la Méditerranée
Nice, France

IEEE RFID 2013

Co-located with RFID Journal LIVE! 2013
April 30 – May 2, 2013
Orange County Convention Center
Orlando, FL USA
www.ieee-rfid.org



Orange County Convention Center
Orlando, FL USA

IEEE RFID 2014

Co-located with RFID Journal LIVE! 2014
April 8 – 10, 2014
Orange County Convention Center
Orlando, FL USA
www.ieee-rfid.org